

# Anomalous training effect in exchange-biased MnPd/Co bilayers

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Abstract: Exchange bias has been studied for a series of MnPd/Co bilayers sputtered onto Si(100) by an RF sputter-deposition system. The double-shifted loops with an anomalous training effect have been observed. The manifestation of double-shifted loops is interpreted as the coexistence of positive exchange bias and negative exchange bias, which is in agreement with the temperature dependence and the observed anomalous training effect. © 2009 WILEY-VCH Verlag GmbH & Co. KGaA, Weinheim.

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